

# RD39 Status Report 2010

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<http://rd39.web.cern.ch/RD39/>

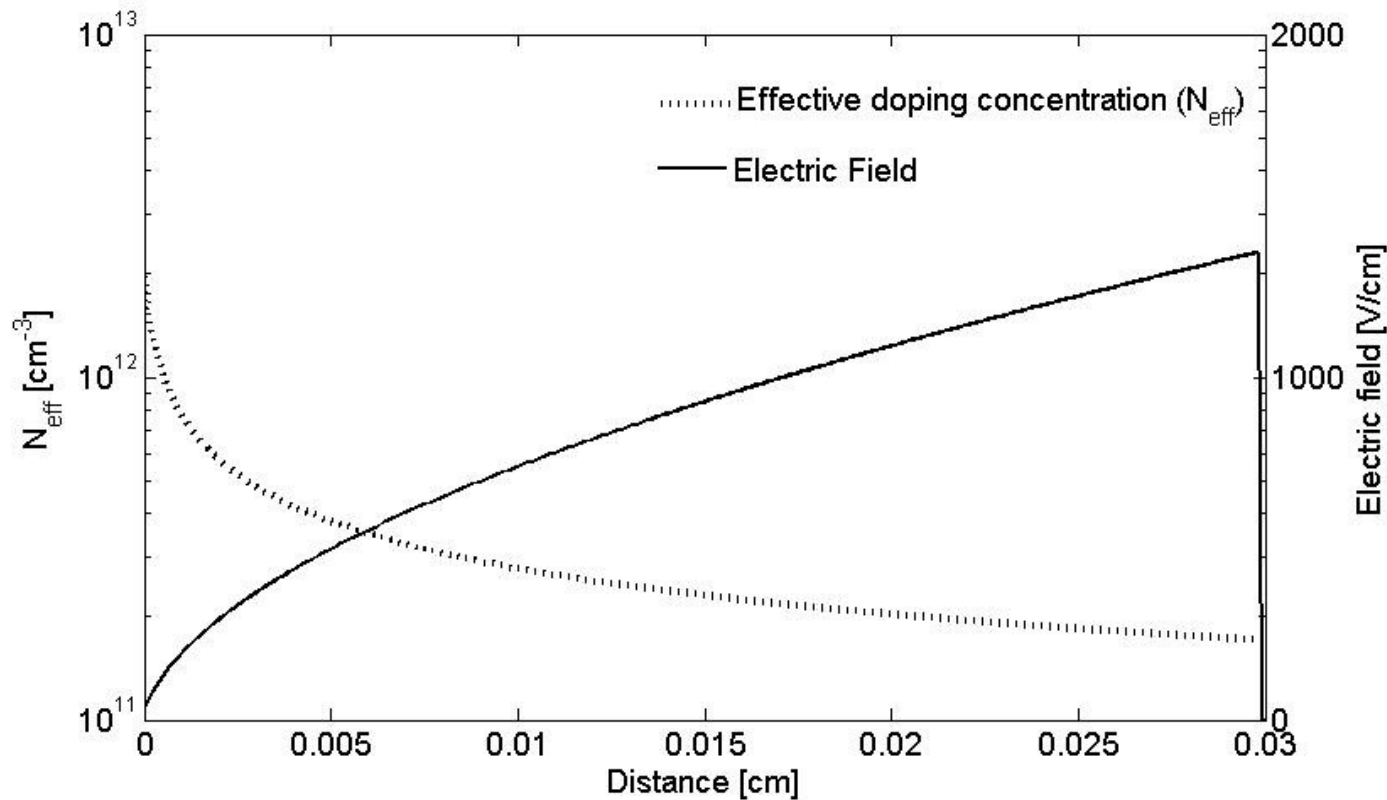
## Outline

- **Principle of Charge Injected Detector (CID)**
- **Summary of previous planar CID test beam results.**
- **New 3D-Trench-CID**
- **Proposed new cryogenic project --- LHC beam loss monitor**
- **Summary**

## Charge Injected Detector (CID) –Operational Principle

The electric field is controlled by charge injection, i.e. charge is trapped but not detrapped at “low” temperature

$$\tau_{trapping} = \frac{1}{\sigma_{e,h} v_{th} N_t} \quad \tau_{detrapping} = \frac{1}{\sigma_{e,h} v_{th} e^{\frac{-E_t}{kT}}}$$



Electric field is extended through entire bulk regardless of irradiation fluence.

Electric field is proportional to square of distance  $E(x) \sim \sqrt{x}$

Detector is “fully depleted” at any bias or irradiation fluence

The trapping is reduced by injection

# New strip detectors for CID studies

Substrate	Thickness [ $\mu\text{m}$ ]	Resistivity [ $\text{k}\Omega\text{cm}$ ]	Design
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Fz-P	300	5-10	N-P-N
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Fz-N	300	5-10	P-N-N
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Fz-N	600	5-10	P-N-N
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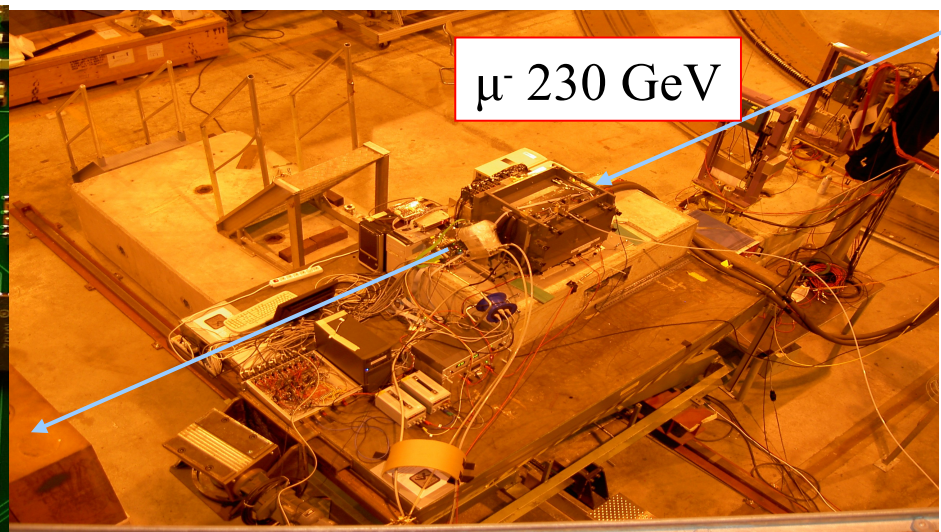
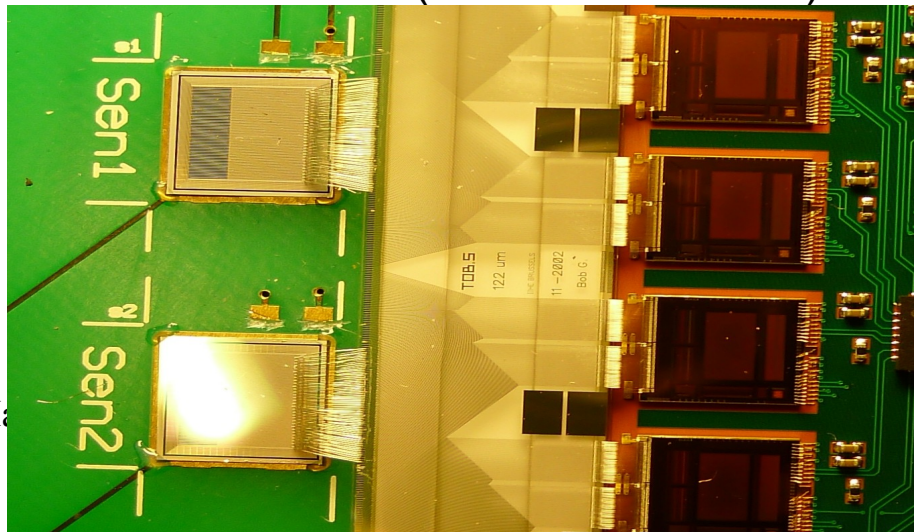
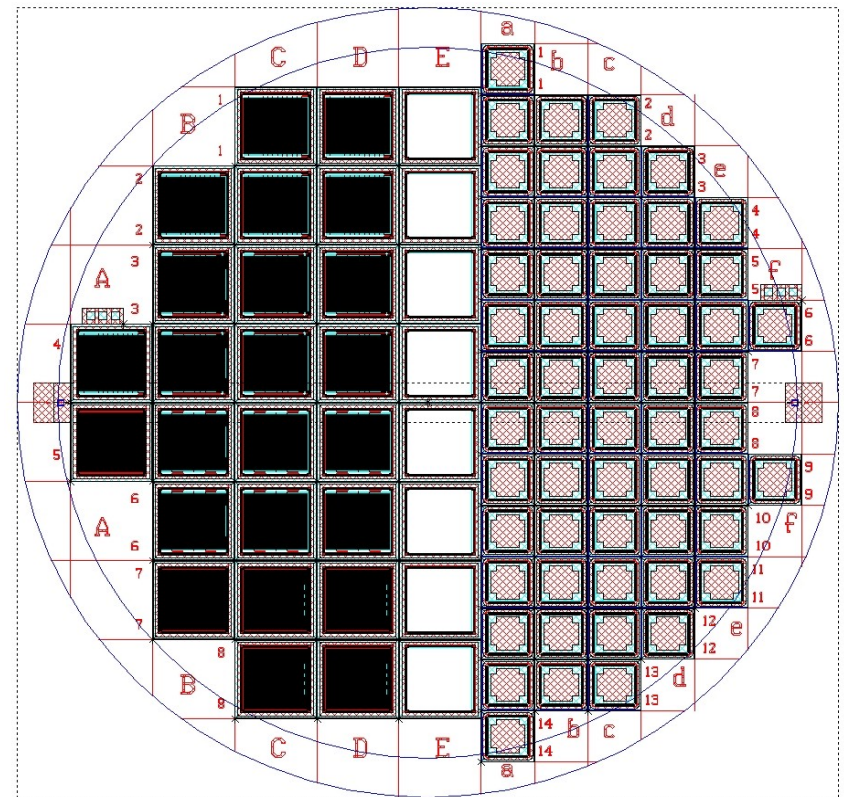
Fz-N	300	5-10	P-N-P
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Fz-N	600	5-10	P-N-P
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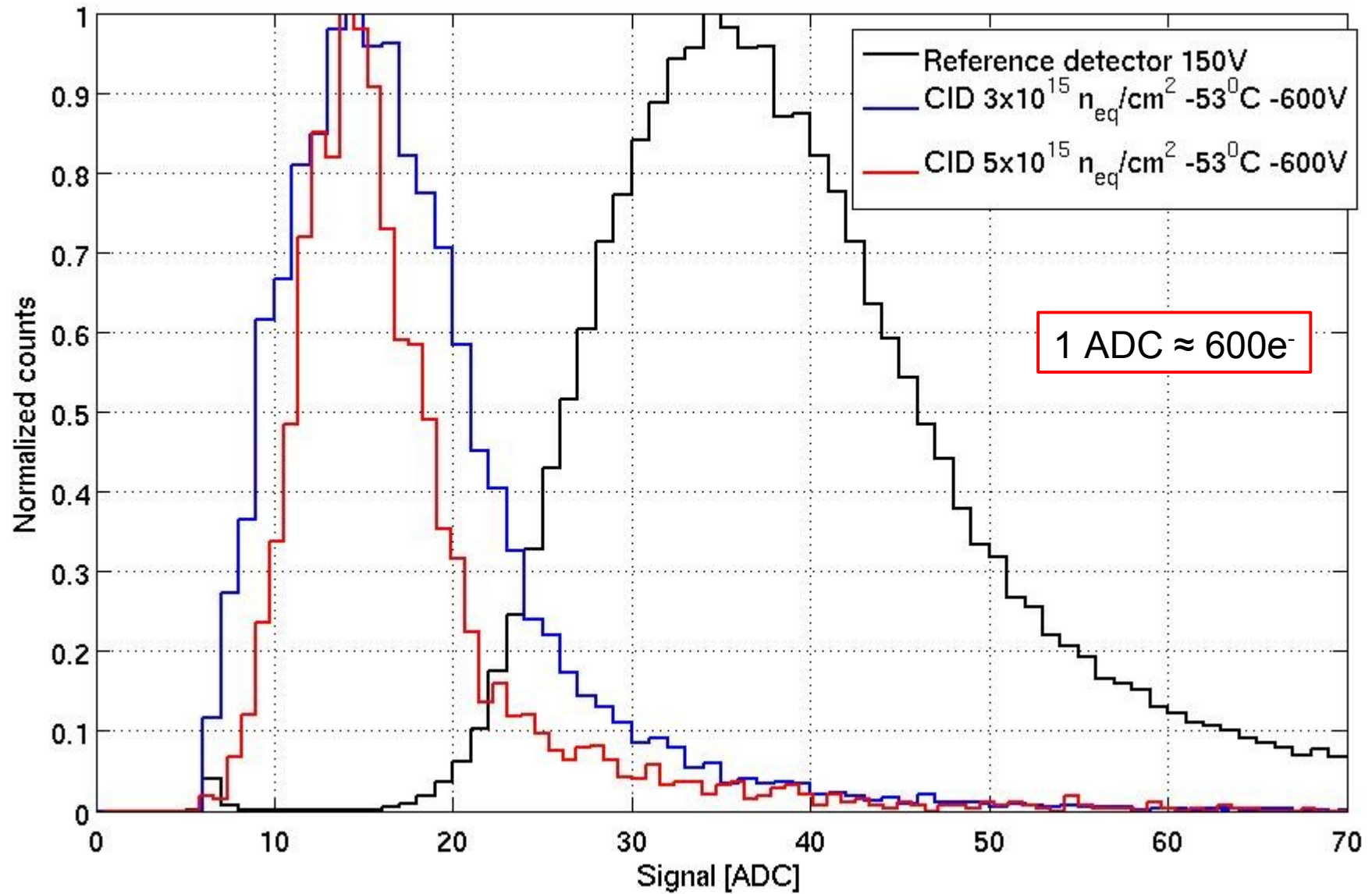
Fz-N	300	2-4	P-N-P
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For test beam studies good quality reference modules are needed (done in Nov 2010)

Purpose is to study how the charge injection influences on detector performance



# Summary plot of planar MCZ CID results

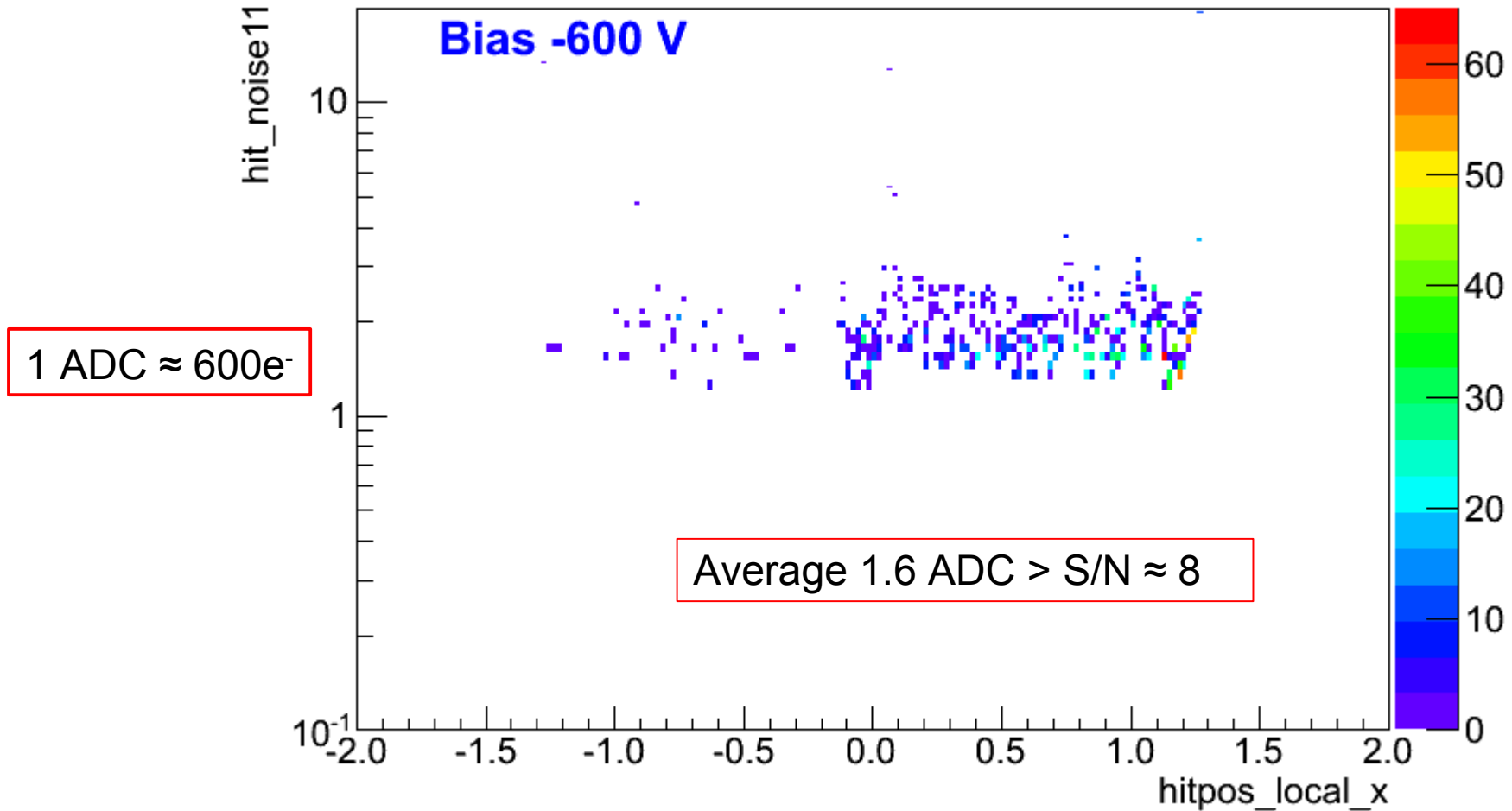




# $5 \times 10^{15} \text{ n}_{e q} / \text{cm}^2$ results - Noise

Run 2130

Entries 9790



# 3D-Trench Electrode detector at CID mode --- New CERN RD39 Rad-Hard Detector Initiative

More efficient charge injection to fill the traps

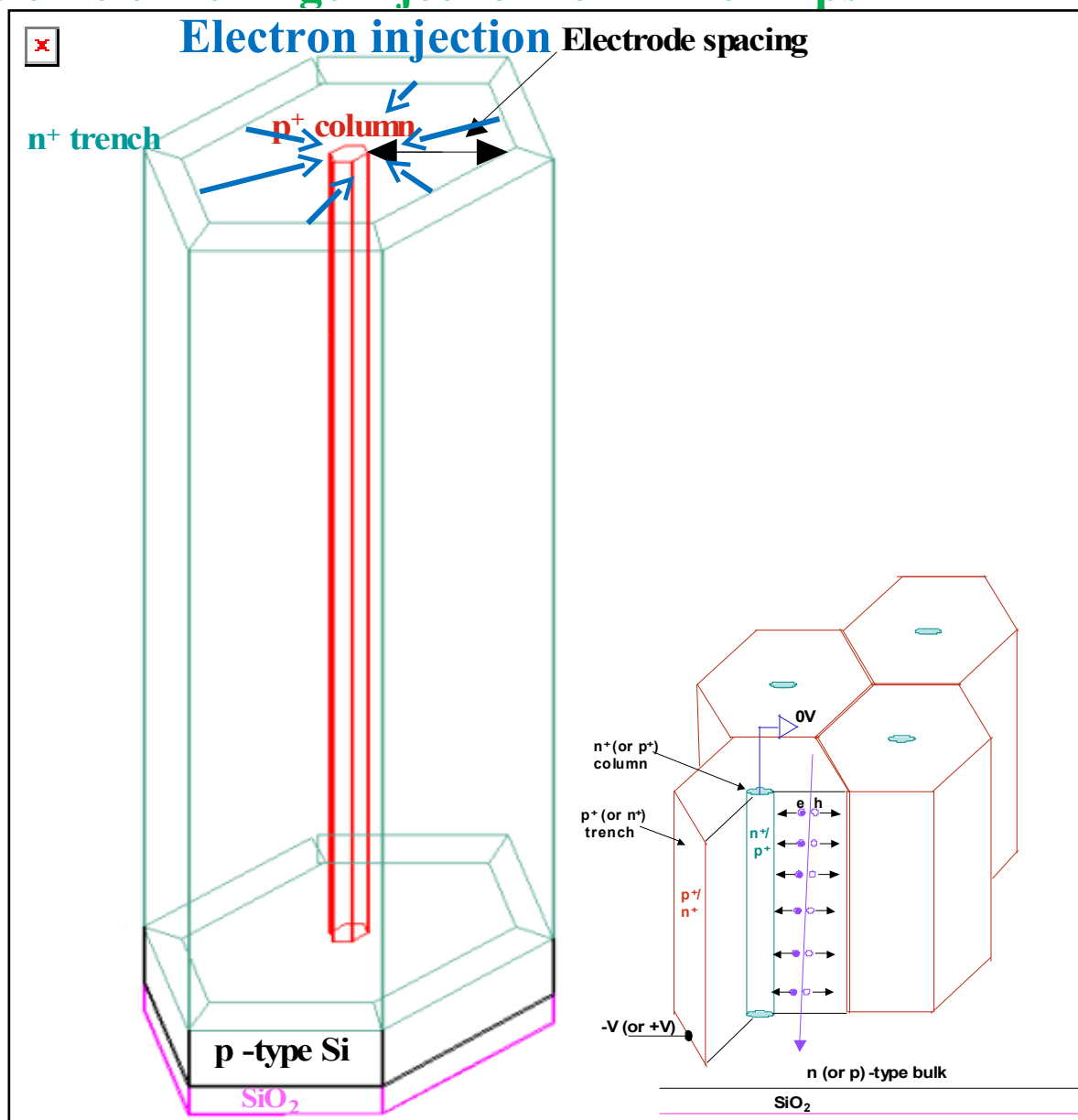


Fig. 1 Schematics of a single cell and array of a concentric type ICDA with outer ring junction (ICDA-ORJ)

**Independent-Coaxial-Detector-Array (ICDA):**

**No cross talks between cells**

23 March, 2011

Z. Li, 2011-001 LHCC O Zheng Li, 15th CERN RD50 Workshop, CERN, 11-18-2009

**3D-Trench-Electrode Detector**  
**ICDA: Independent-Coaxial-Detector-Array**

US patent pending (61/525,756)  
BNL PCT filled on 10/15/2010 (PCT/US2010/52887)

## Cylindrical geometry used for the simulation for 3D-Trench CID

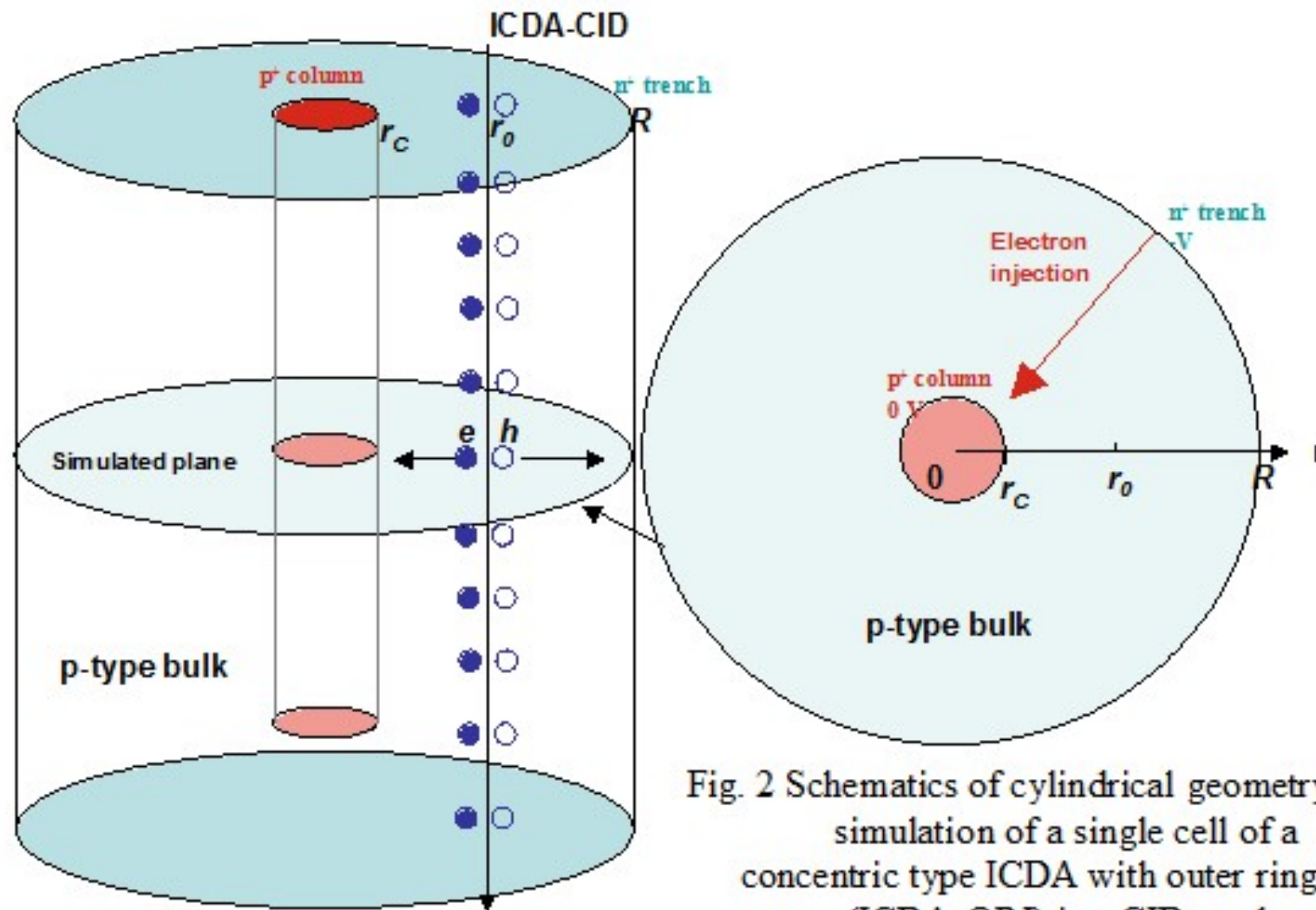
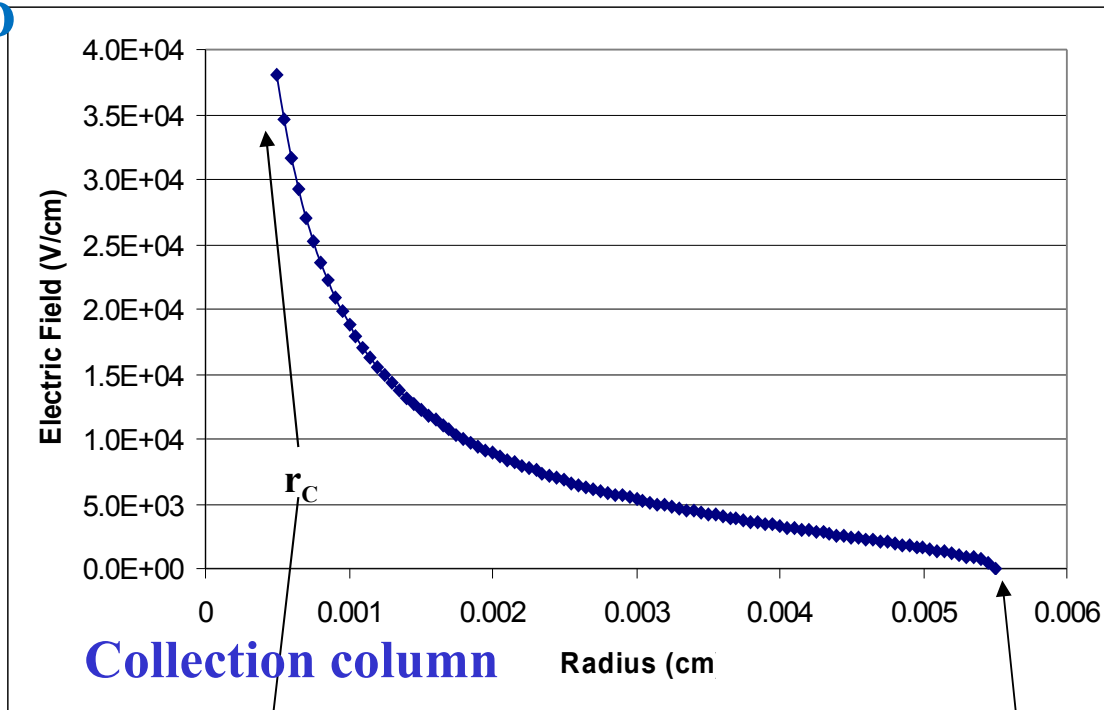


Fig. 2 Schematics of cylindrical geometry for the simulation of a single cell of a concentric type ICDA with outer ring junction (ICDA-ORJ) in a CID mode

# Electric field and weighting field profiles in a 3D-Trench

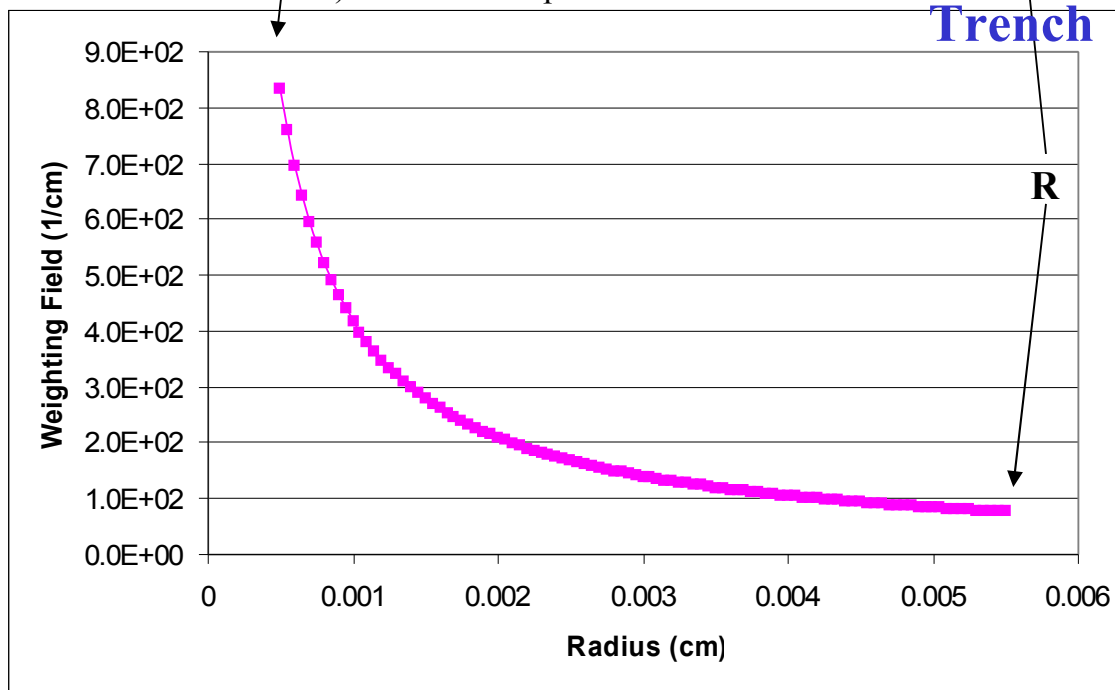
CID



Collection column

Similar shapes

a) Electric field profile

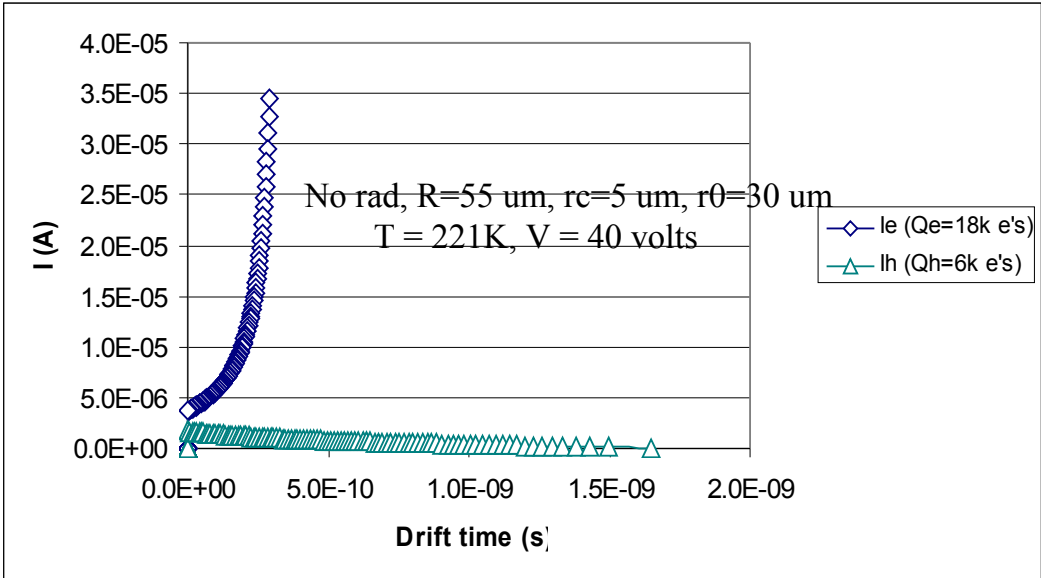


Trench

b) weighting field profile

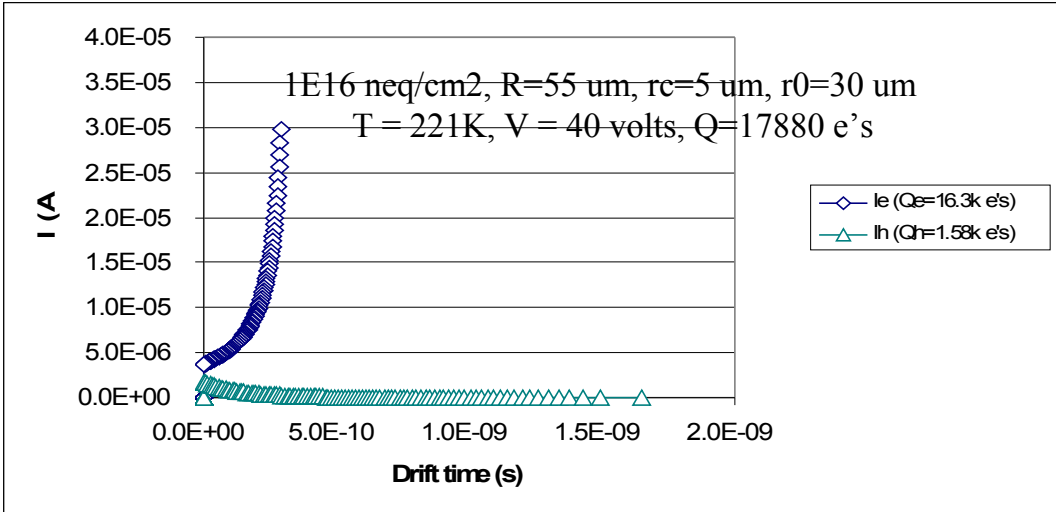


**Electron and hole current shapes induces by a MIP for a non-irradiated 3D-Trench CID**



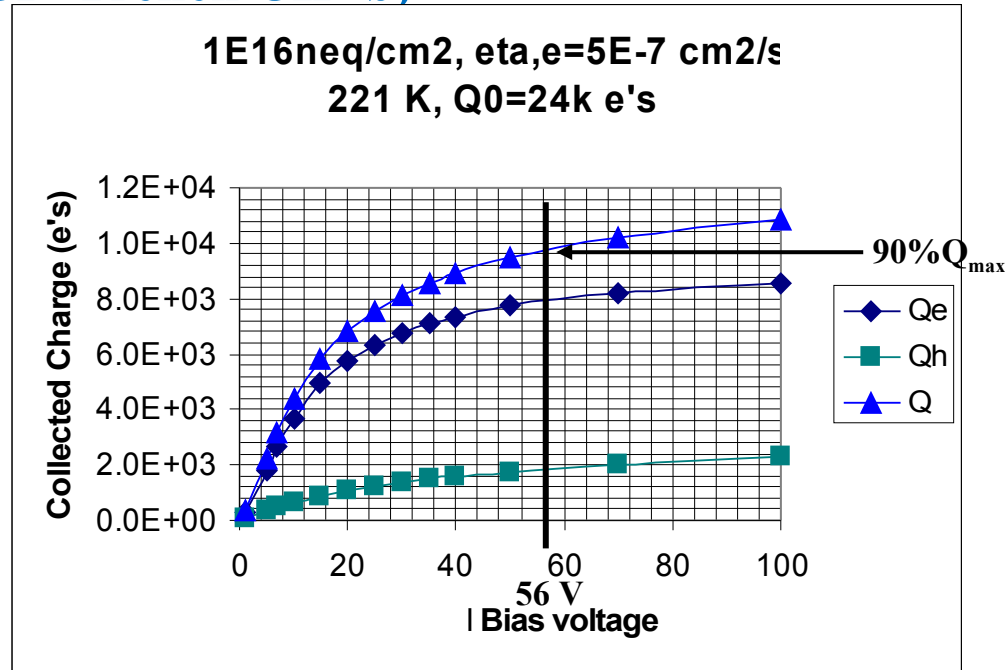
**Total collected charge mostly contributed by electrons due to weighting field**

**Electron and hole current shapes induces by a MIP for an irradiated 3D-Trench CID**

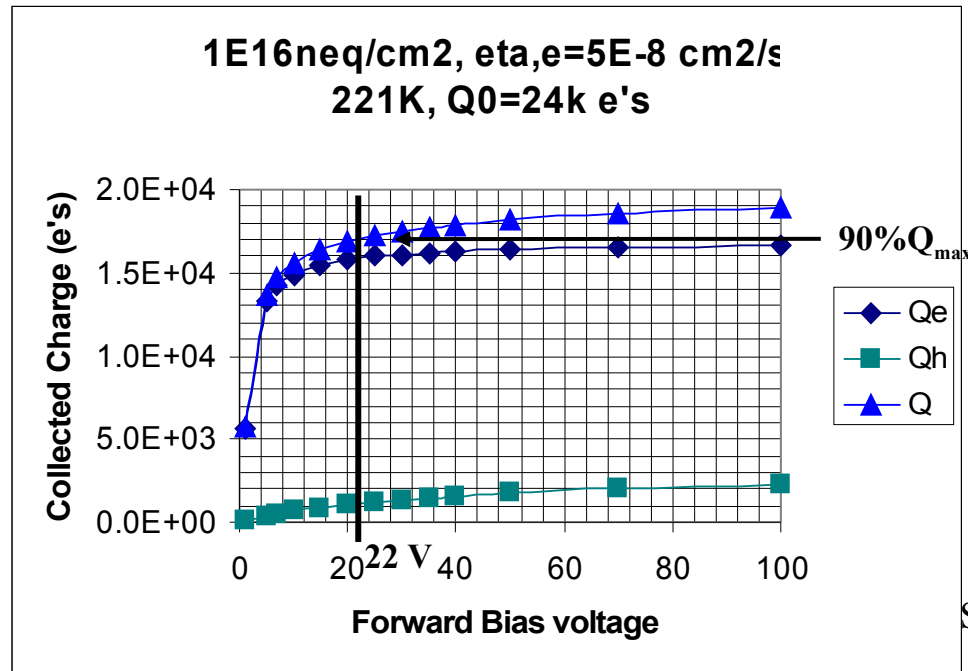


**Total collected charge almost all contributed by electrons due to Weighting field and trapping**

# Total collected charge vs. bias voltage for a 3D-Trench detector a) and a 3D-Trench CID b)



a) Non-CID mode

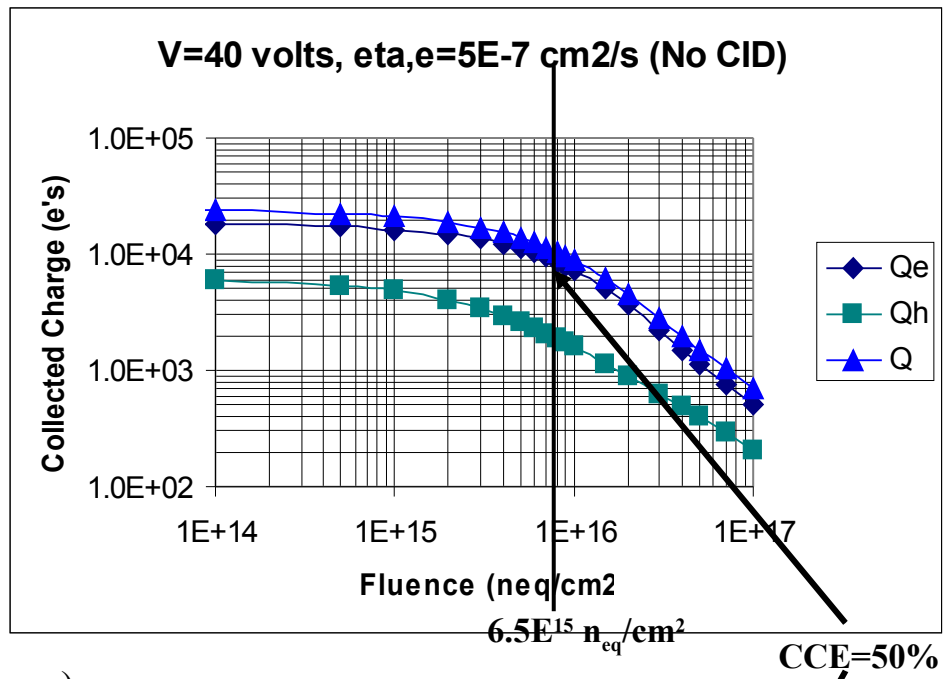


b) CID mode

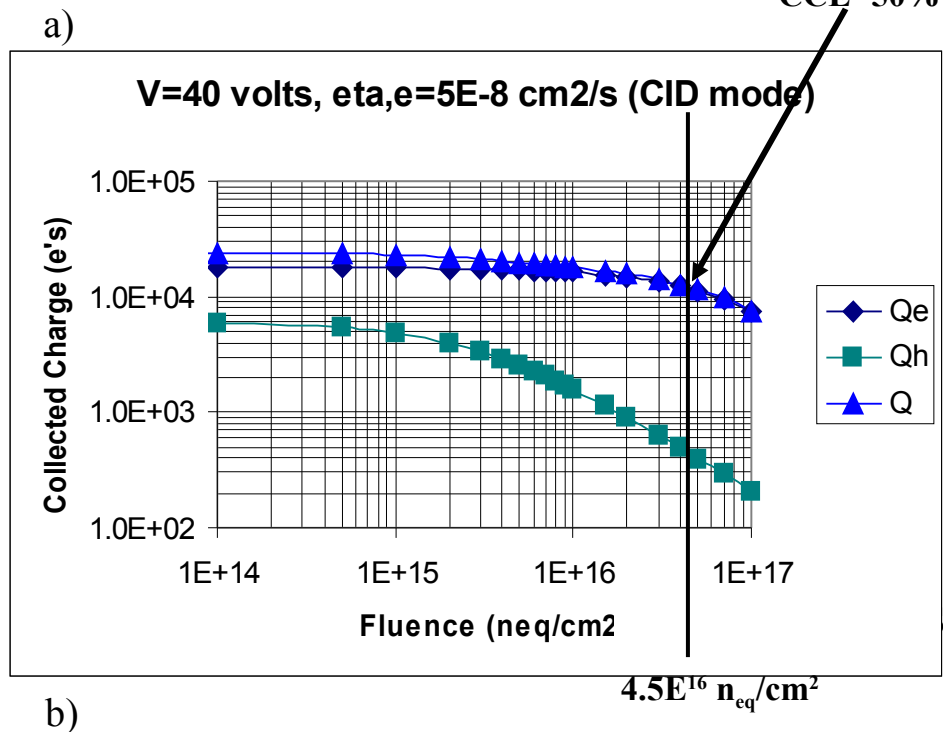
$$\frac{1}{\tau_t} = \eta_0 \cdot \Phi_{n_{eq}}$$

Total collected charge in a 3D-trench CID is much more, and at much less Bias voltage

# Total collected charge vs. fluence for a 3D-Trench detector a) and a 3D-Trench CID b)



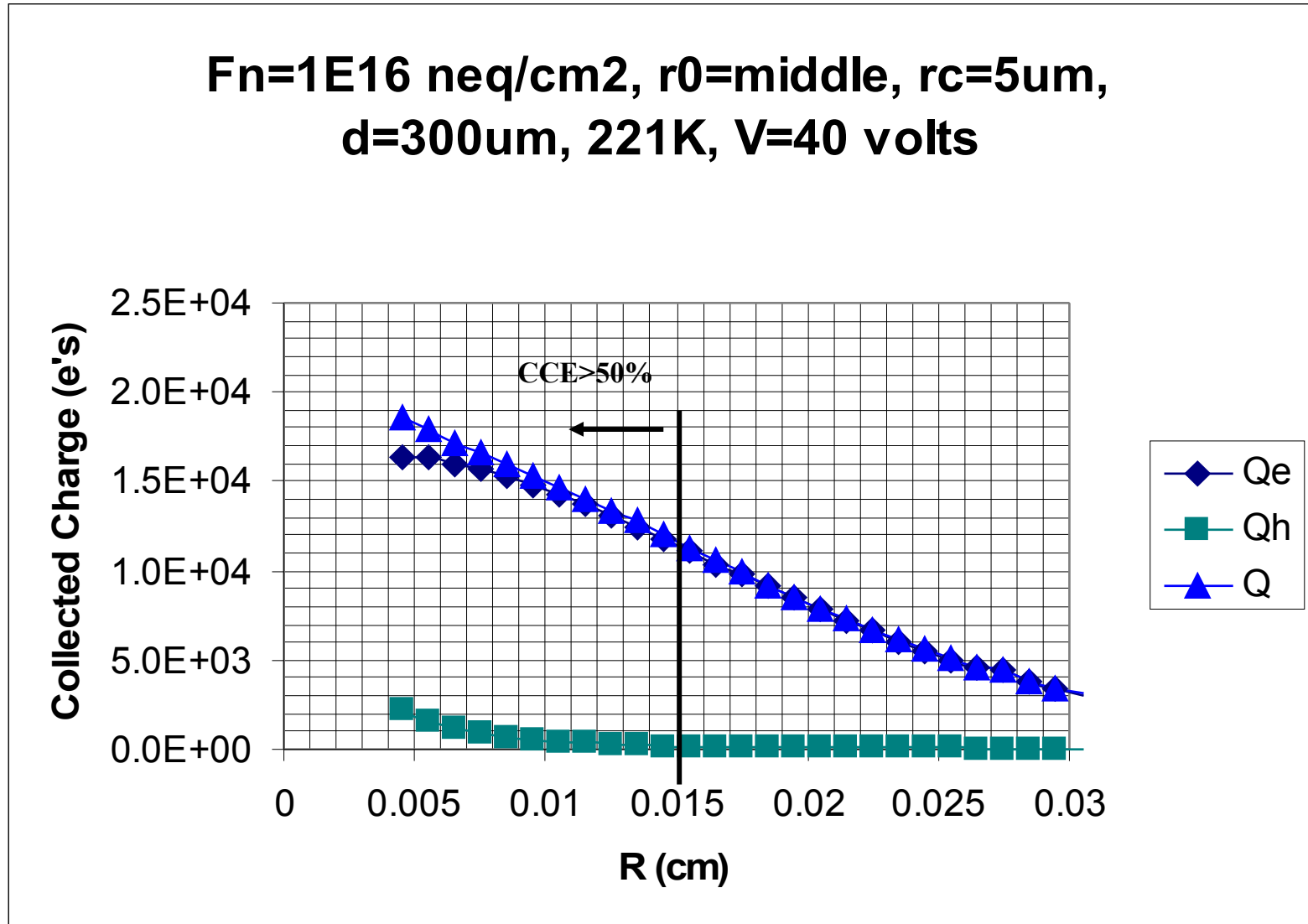
For the same CCE, the fluence range in 3D-Trench CID can be 6 times higher than standard 3D-Trench detector



For planar CID, CCE is about 30% at  $1 \times 10^{16}$  n<sub>eq</sub>/cm<sup>2</sup>

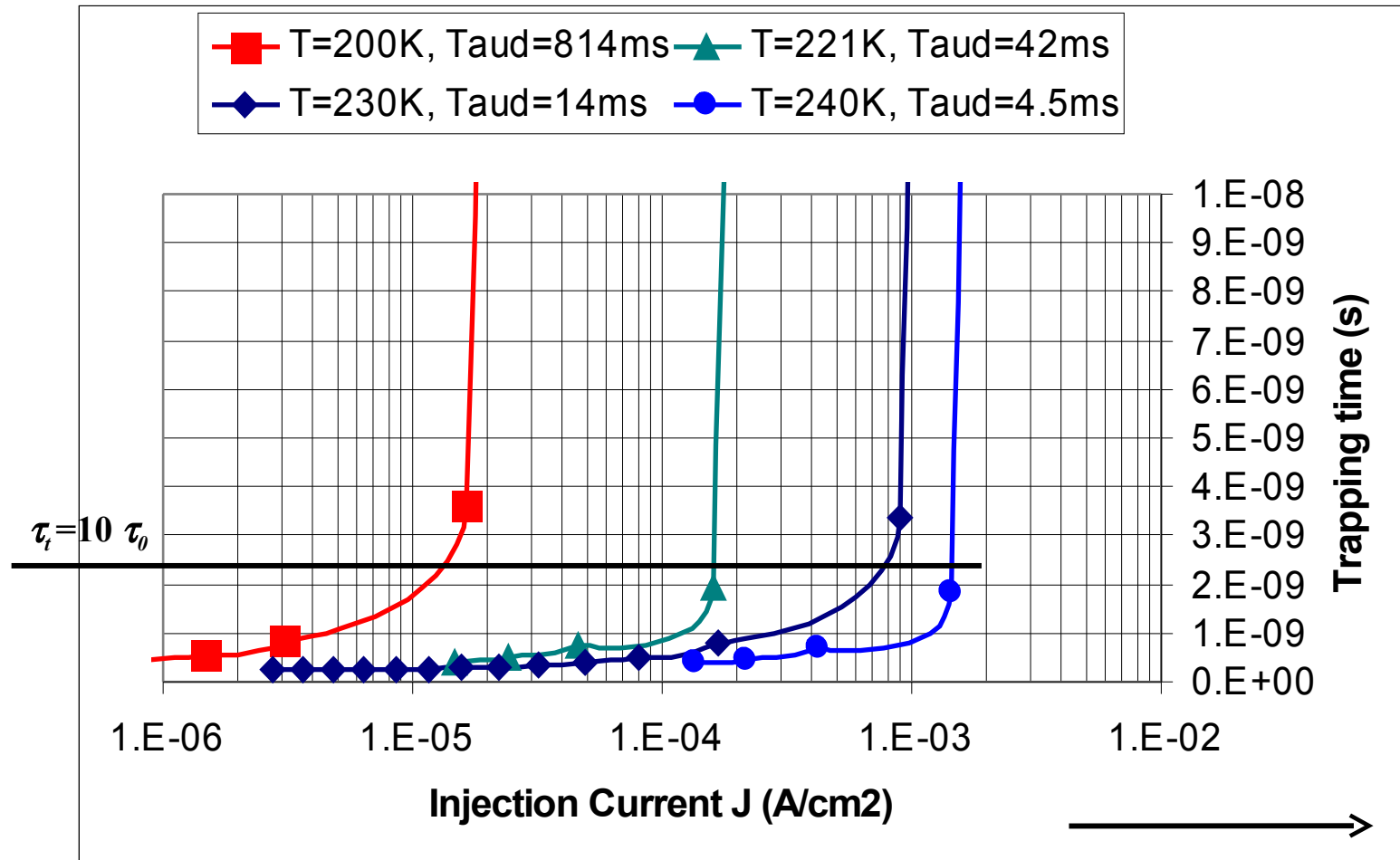
## CCE dependence on R (trench radius) in a 3D-Trench CID

$F_n=1E16$  neq/cm<sup>2</sup>,  $r_0$ =middle,  $r_c=5\mu\text{m}$ ,  
 $d=300\mu\text{m}$ , 221K,  $V=40$  volts



# Charge injection induced reduction in trapping (increase in trapping time) Dependence on Temp

$$N_T = 0.5 * \Phi_n, \Phi_n = 1.0 \times 10^{16} \text{ cm}^{-2}, E_t = 0.53 \text{ eV}, \sigma = 1.0 \times 10^{-13} \text{ cm}^2, \tau_{t0} = 0.23 \text{ ns}$$

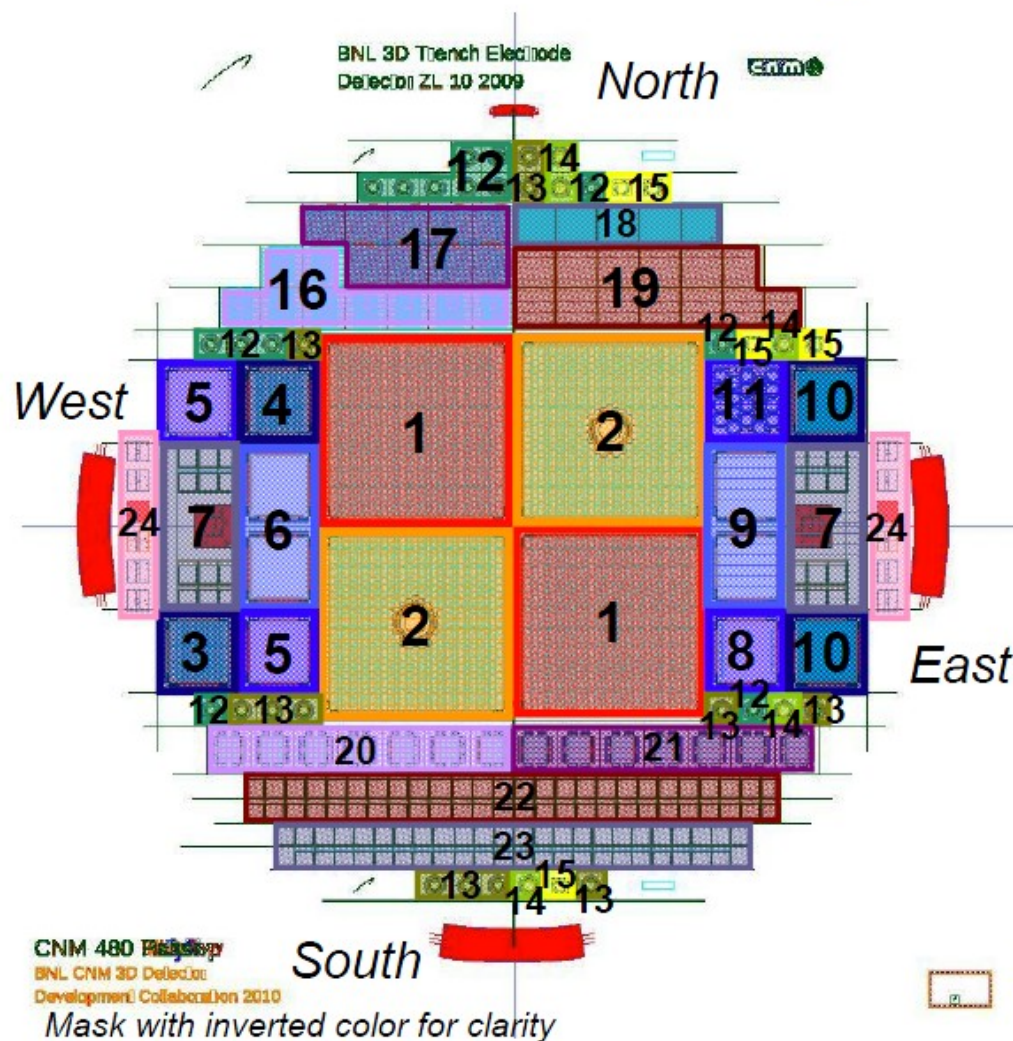


**The higher the temp, the more the injection needed**



Fabrication of the first prototype batch of BNL 3D-Trench-Electrode detectors are under way in CNM of Spain (Giulio Pellegrini), completion expected in summer 2011

# CNM480 – trenched detectors for BNL (Zheng-Li)

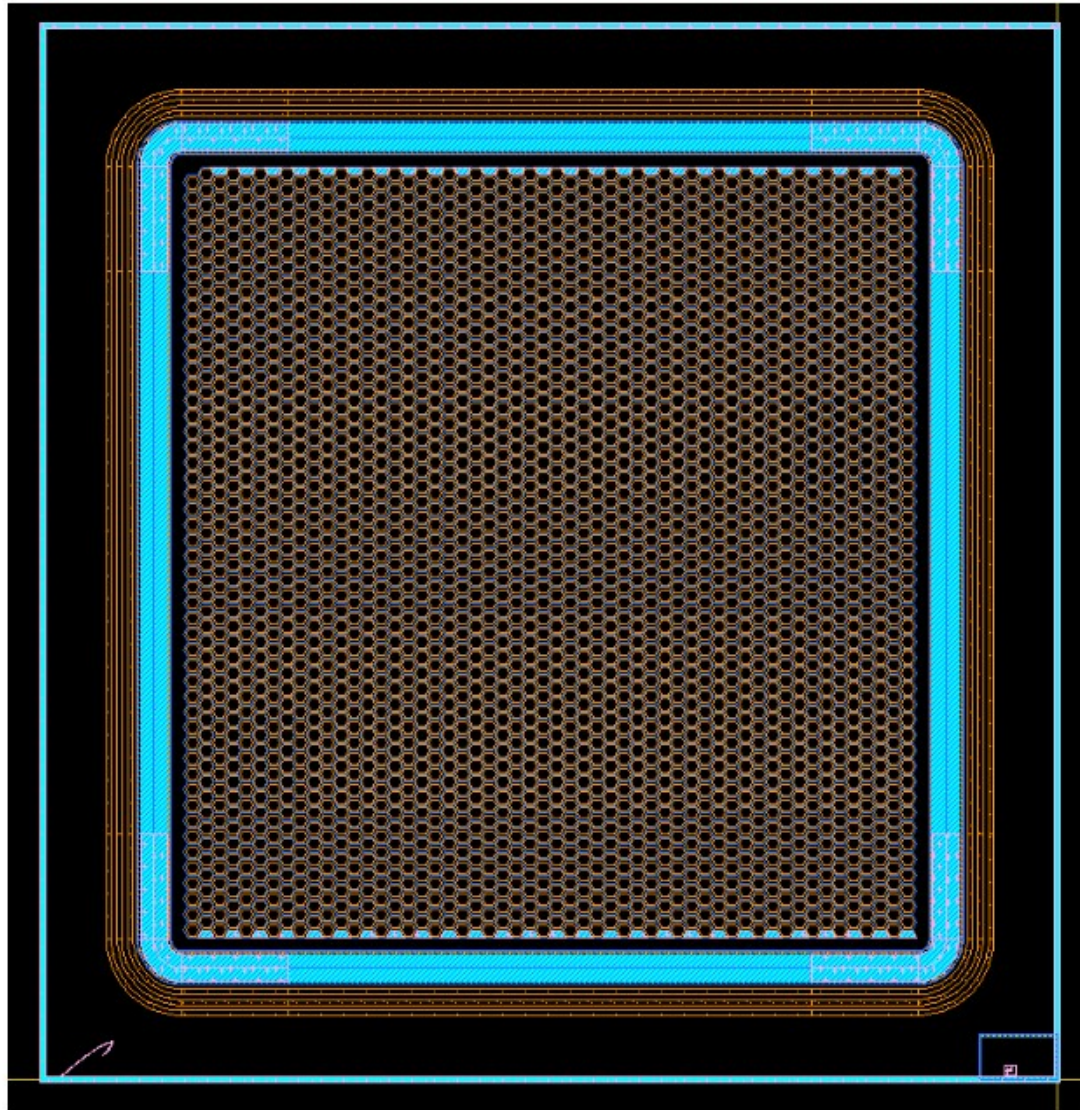


Ref.	Name	Qty
1	3D_TRENCH_PIXEL_HEX_R500_0	2
2	3D_TRENCH_PIXEL_HEX_R500_1	2
3	3D_TRENCH_PIXEL_HEX_R500_2	1
4	3D_TRENCH_PIXEL_HEX_R500_7	1
5	3D_TRENCH_PIXEL_HEX_R80_70	2
6	3D_TRENCH_PIXEL_SQU_R212_7	2
7	3D_TRENCH_PIXEL_SQU_R212_1	4
8	3D_TRENCH_PIXEL_CIR_R300_7	1
9	3D_TRENCH_STRIPIXEL_SQU_R2	2
10	3D_TRENCH_STRIPIXEL_REC_16	2
11	3D_TRENCH_DRIFT_CIR_R500_1	1



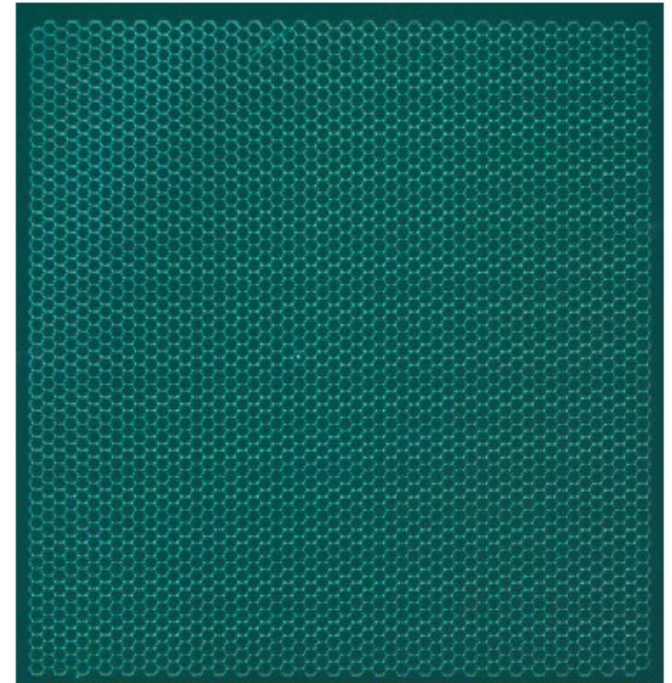
**One example:  
Hexangular type,  $R = 80 \mu\text{m}$ , 49x54 array**

**Design**

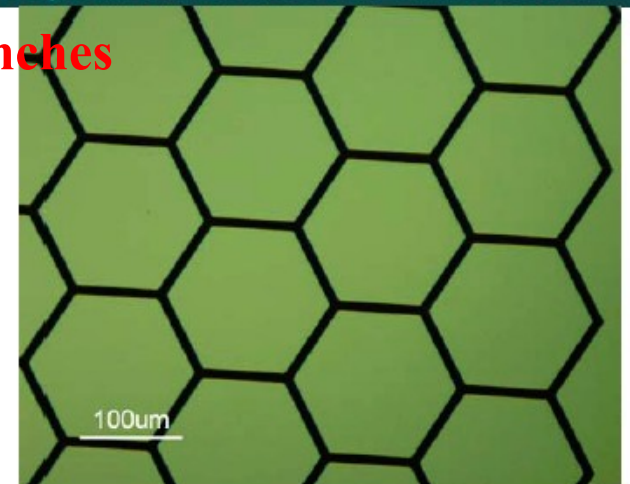


**Etched trenches**

*Pics from run5645*



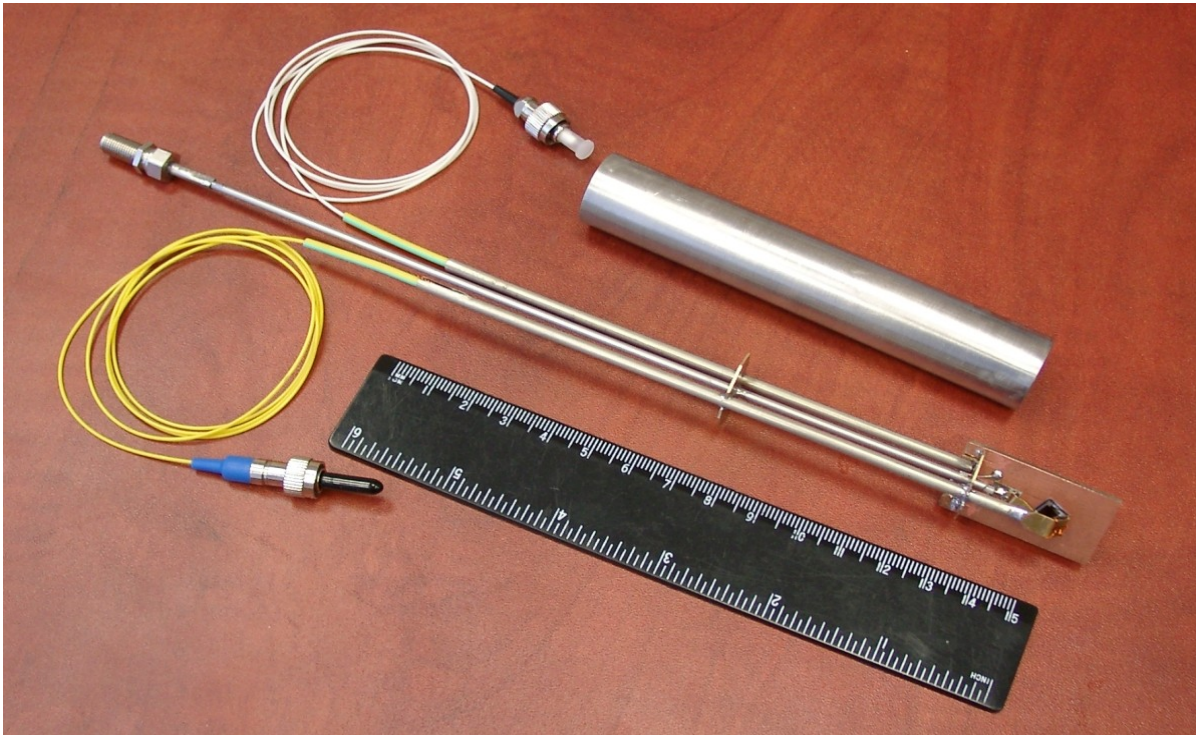
**trenches**





# Proposed new cryogenic detector projects

- LHC Beam Loss Monitor



- Must operate at LHe temperature
- Must be radiation hard
- Probably operates in CID mode

Ongoing testing with RD39  
cryogenic TCT (alpha source and  
laser)

Beam Loss Monitor prototype for testing

## Summary

- **New planar CID strip detectors with various configurations and thickness have been designed and made, and reference detectors have been beam tested**
- **New 3D-Trench-CID detectors have been extensively modeled and simulated;**
- **The CCE of these 3D-Trench-CID detectors are predicted to be much higher at much less bias voltages;**
- **the first prototypes of 3D-Trench-CID detectors are being made, and will be tested this coming year;**
- **The work for the proposed new cryogenic project --- LHC beam loss monitor has now being under way.**